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DRIE Technology For MEMS



Plasma Etch Users Group, 26 February, 2009

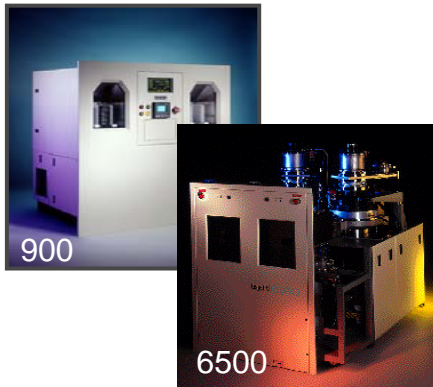
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- ◆ Introducing Tegal Products
- ◆ MEMS Feature Size Requirements
- ◆ The Bosch DRIE Process
- ◆ Silicon DRIE Technology
 - Scallop Control
 - Etch Rate
 - Angle deviation
 - Thermal Dissipation
 - Notching control
 - ARDE
 - SHARP
 - Process Stability
- ◆ Oxide DRIE

Tegal Products 1

ETCH



Diode, ICP and HRe⁺ CCP Sources

- ◆ Non-volatile memory
- ◆ **MEMS devices**
- ◆ Thin-film head for disk drives
- ◆ Integrated Passives
- ◆ Compound Semiconductors

PVD



Endeavor AT AMS SMT, MMT

- ◆ Advanced Packaging: Under-bump metallization
- ◆ Power device backside metallization
- ◆ **MEMS devices** – AlN BAW FBAR
- ◆ Integrated Passives : Thin film resistors and capacitors

NLD



Compact 360 NLD

- ◆ Thin film barrier
- ◆ Thin film seed
- ◆ Thin film electrode
- ◆ LED encapsulation
- ◆ MIM DRAM
- ◆ High-k dielectrics
- ◆ 300 mm

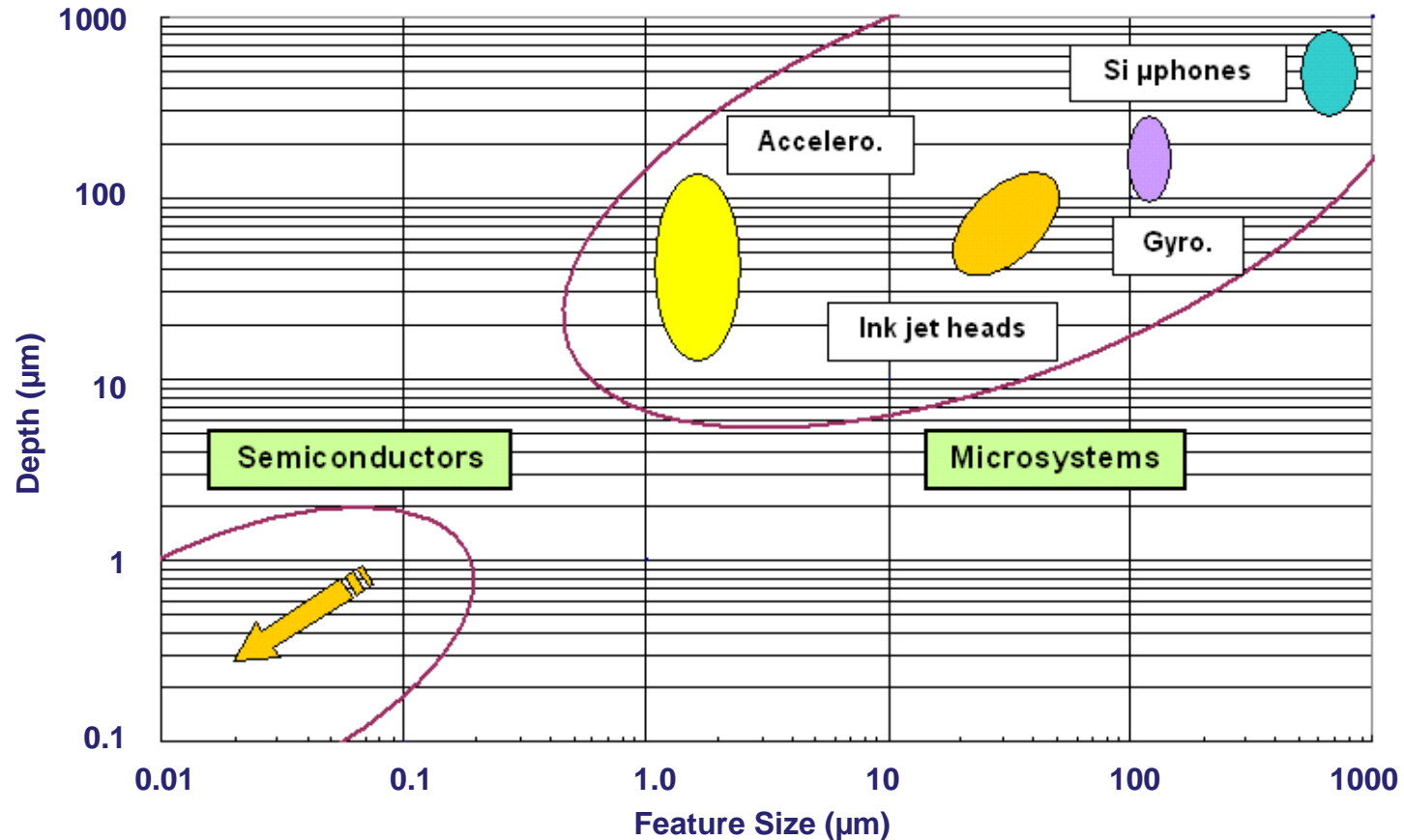
Tegal technology addresses Etch, PVD and CVD

Tegal Products 2



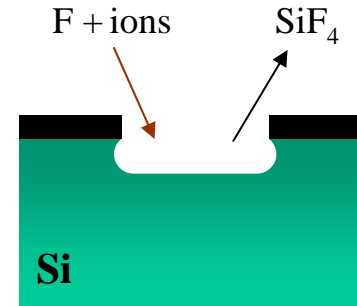
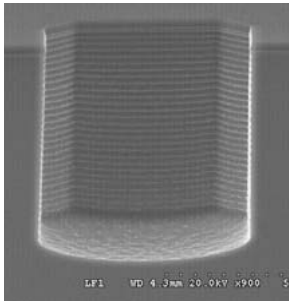
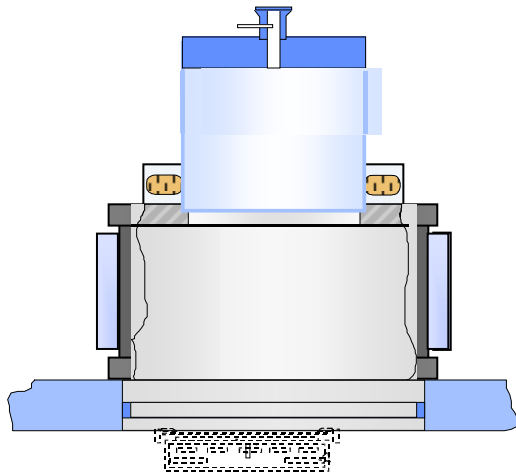
AMMS technology is now part of Tegal,
addressing Deep Silicon Etch and Oxide Etch

Microsystems & Semiconductors

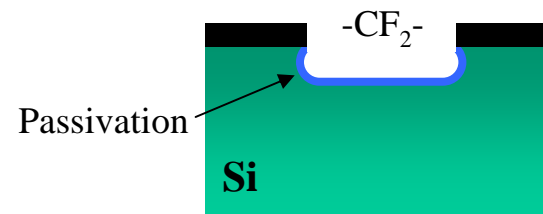


MEMs encompass a wide range of dimensions

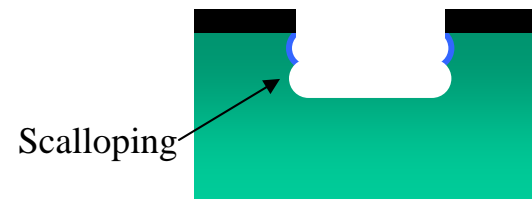
The Bosch DRIE Process



SF₆ Plasma



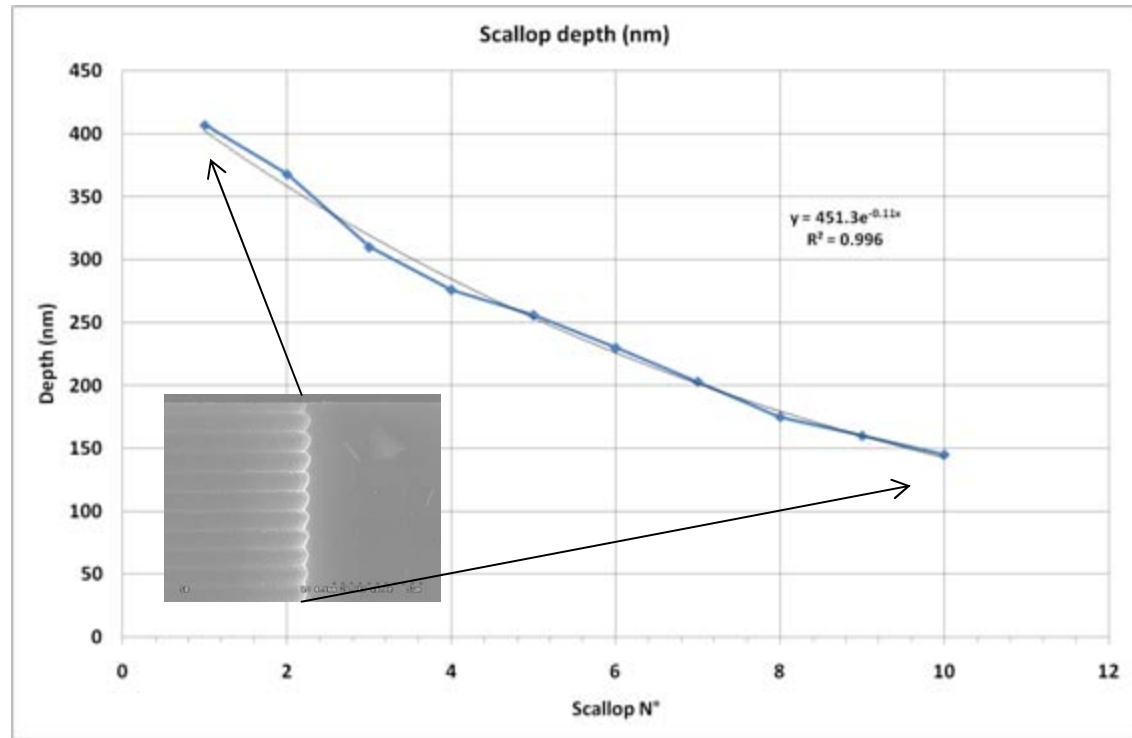
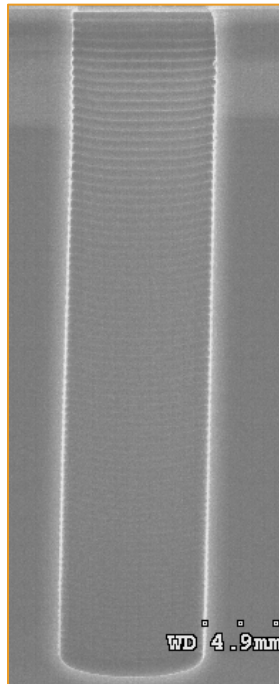
C₄F₈ Plasma



SF₆ Plasma

Bosch: A cyclic process alternating between Etch and passivation

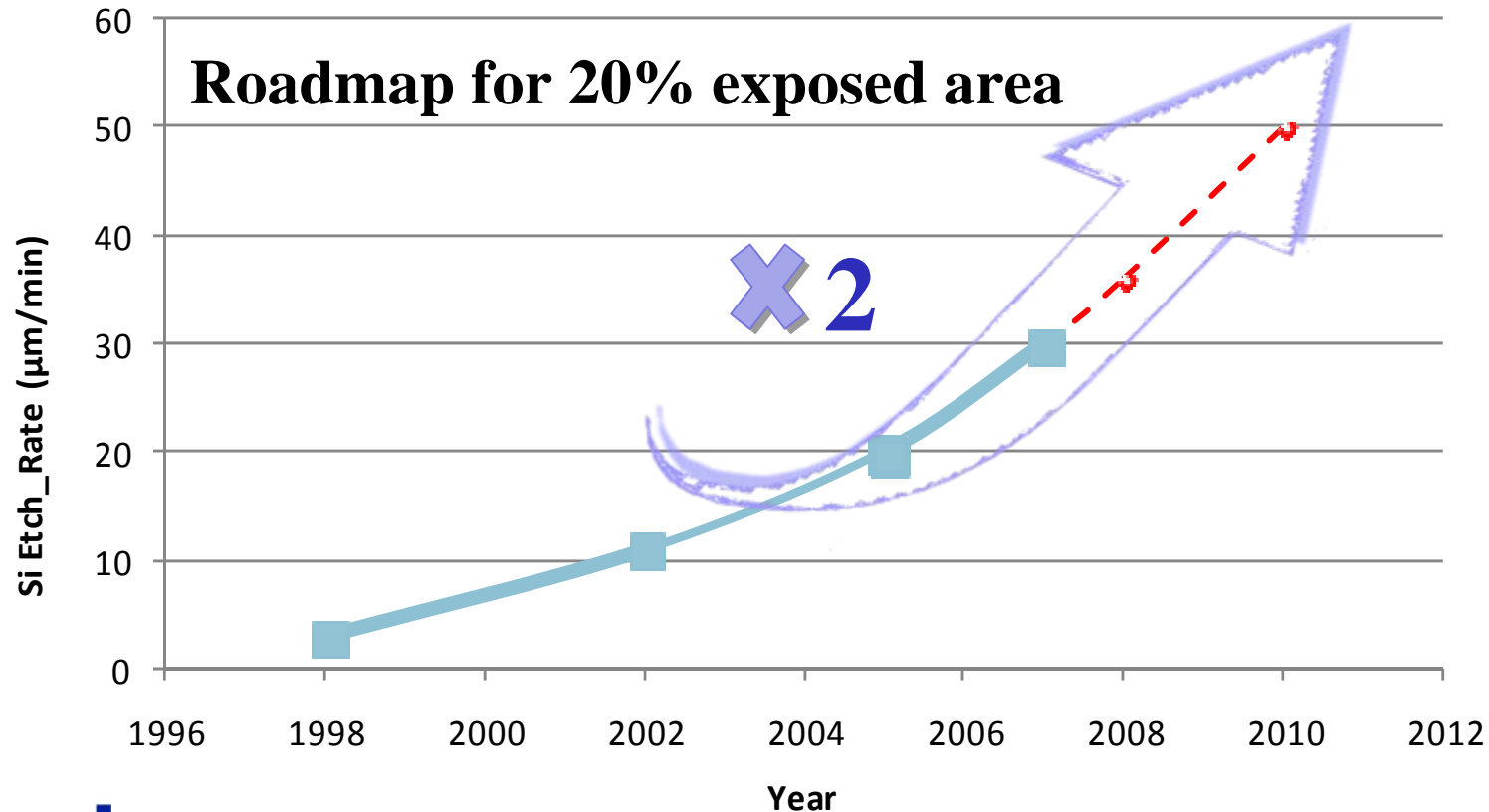
Silicon DRIE – Scallops



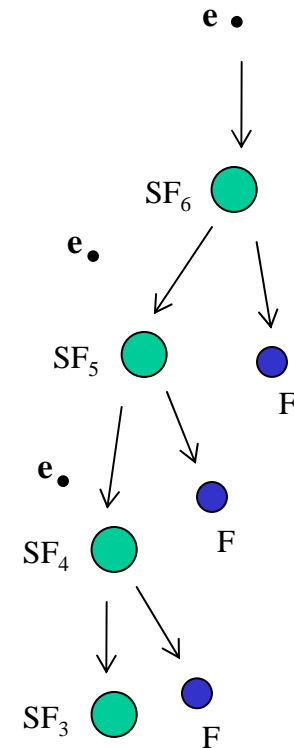
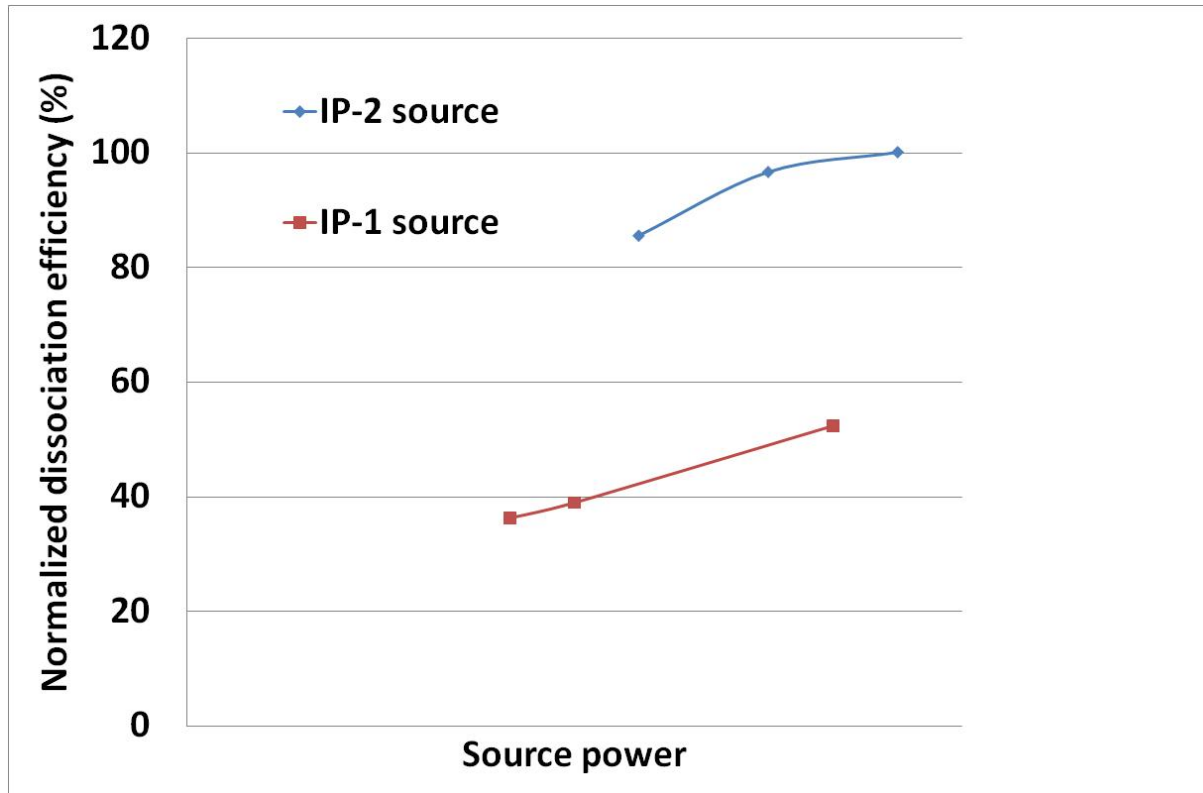
Scallops get smoother with depth, and can be reduced by increasing C_4F_8 during the etch step.

The Race Toward Higher Etch Rate

- ◆ Silicon etching is by “F”, a chemical process with loading effects.
- ◆ Higher gas flow and pressure, better gas utilization are needed.
- ◆ Higher RF Power is needed.

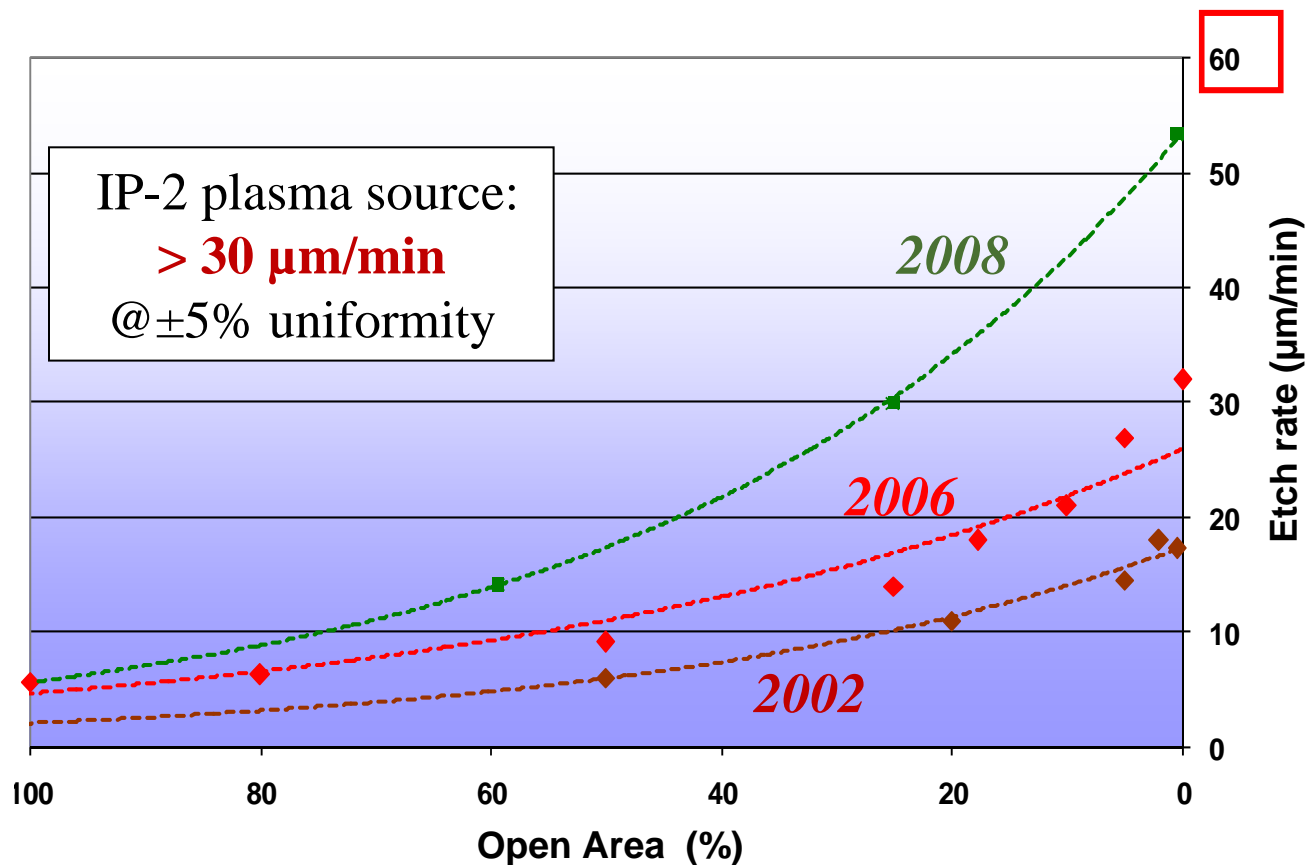


Silicon DRIE - Improved gas utilization



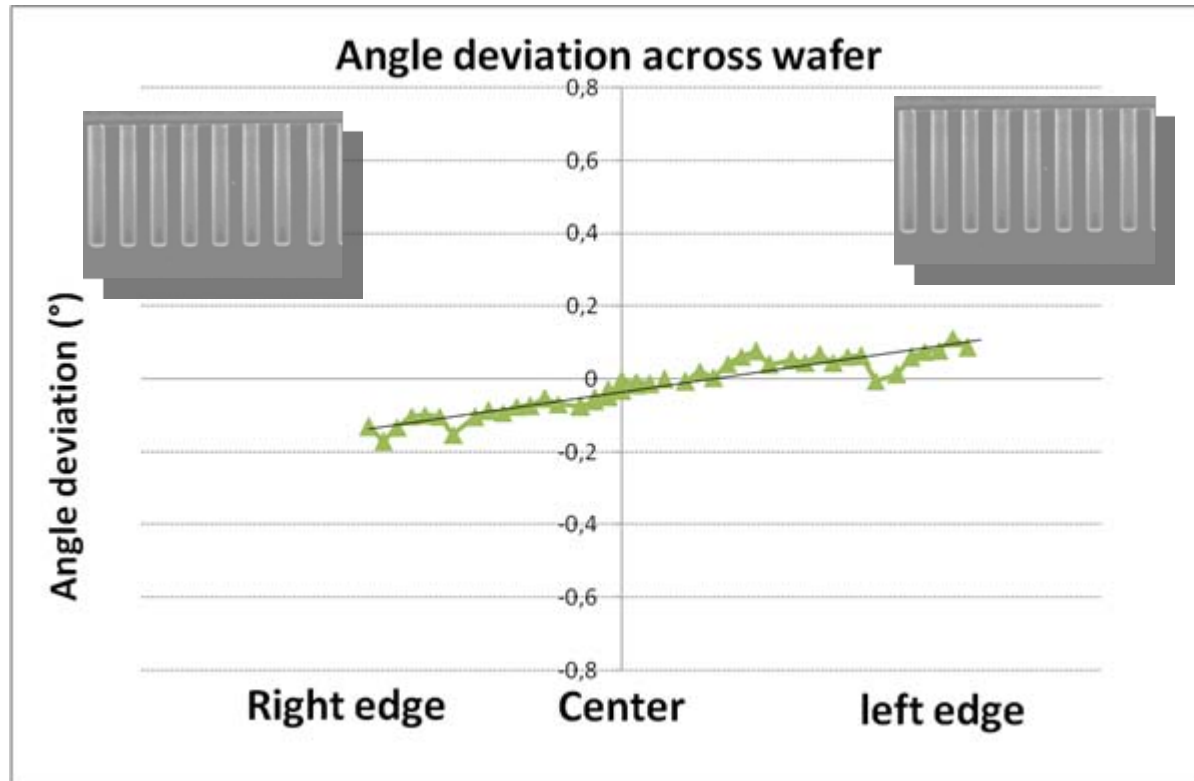
100 % Increase in gas dissociation with IP-2 source

Silicon DRIE - Improved etch rate



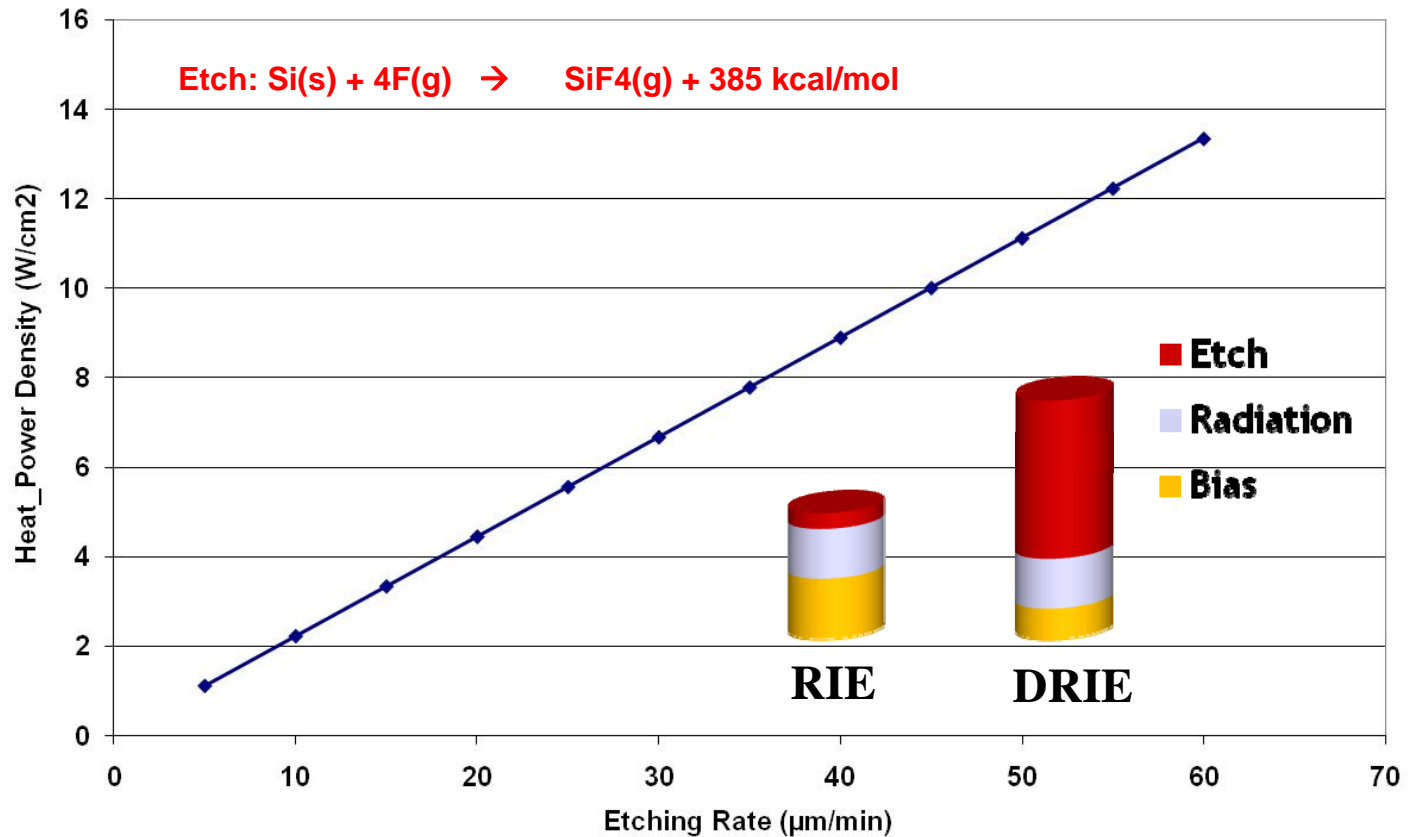
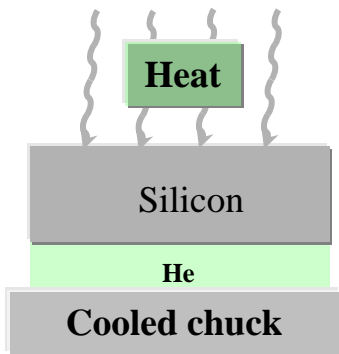
Newest Generation plasma source significantly increases silicon etch rate

Silicon DRIE - Angle Deviation



Gas and plasma uniformity improvements provide tight profile control across the wafer, $< 0.15^\circ$

Thermal Dissipation Issues



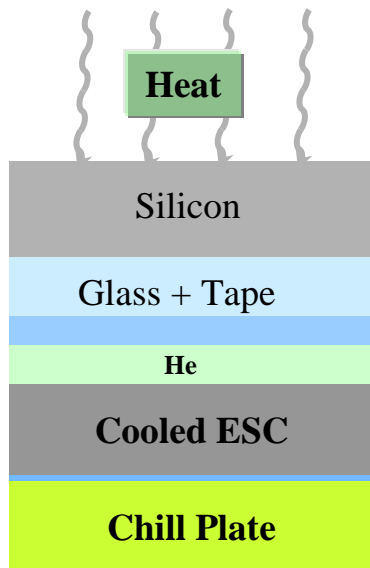
Increasing etch rate inevitably produces more heat to dissipate.

Thermal Dissipation Issues

- ◆ Wafer clamping with He backside pressure is the only way to maintain a low temperature substrate surface.

Thermal conductivity of materials (W/M-K)

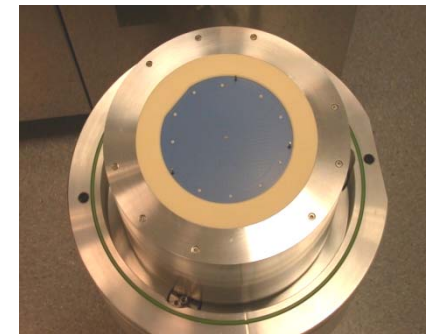
Glass	Alumina	AlN	Kapton	Silicon	Aluminum	Helium
≈ 1	15-30	180	0.16	156	210	0.15



Thermal resistive substrate materials can be a limiting factor for High etching rate and profile control.

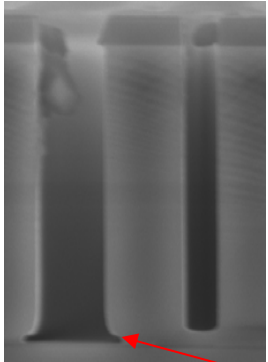
Chill plate interface can impact the ESC cooling effectiveness .

Newest generation ESC design improves wafer cooling efficiency

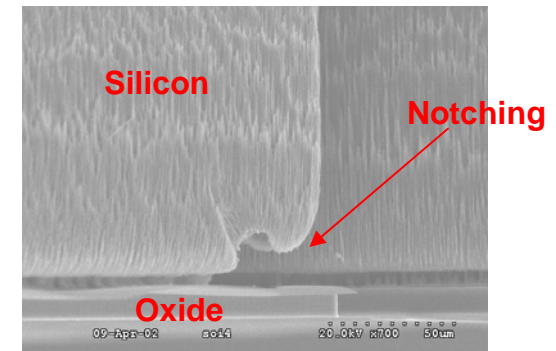
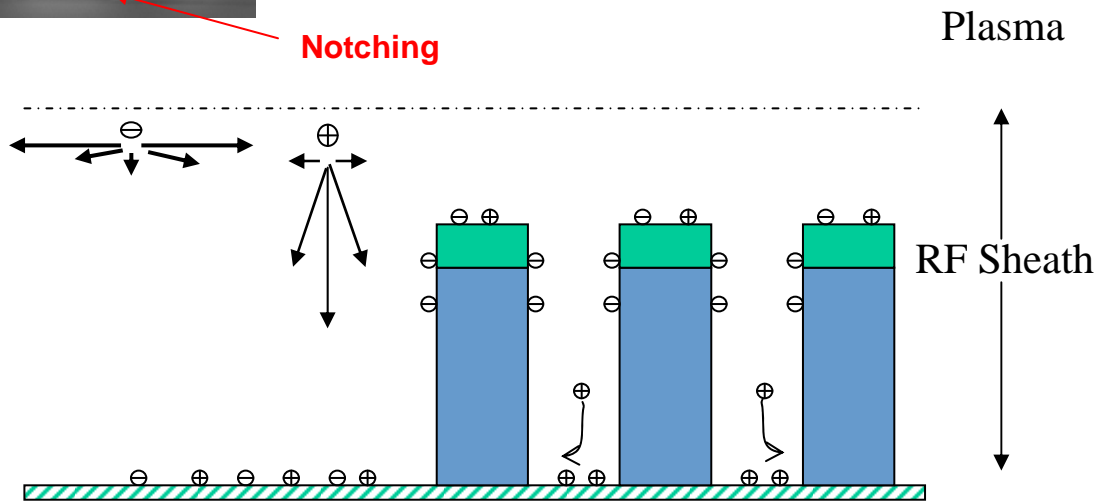


ESC for SOI

MEMS & SOI: notching



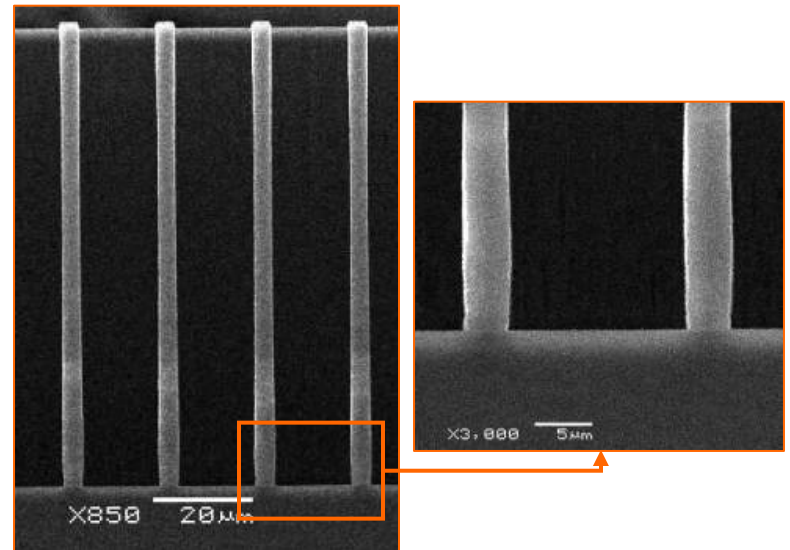
- ◆ Notching is the local side etching of a conductive layer (silicon) above an insulating layer (oxide).
- ◆ Pattern bottoms are charged up by an excess of positive ions, resulting in a divergence of ion trajectories close to the oxide layer.



MEMS devices on SOI substrates require careful attention to notch suppression

How to suppress the notching ?

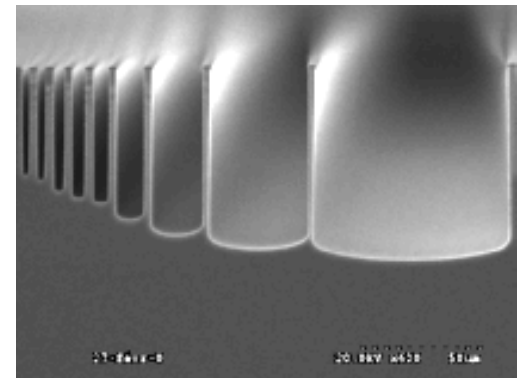
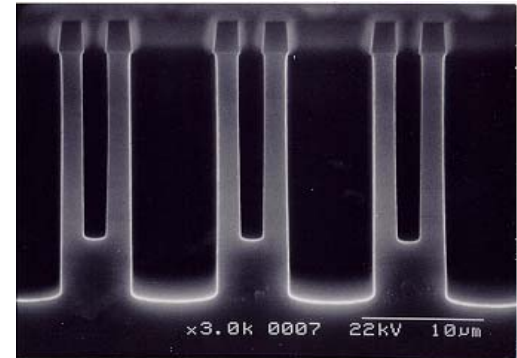
- ◆ 1 - Increase the sidewall protection
 - Protection decreases with Aspect Ratio
 - Net Etch rate tends to zero at higher AR!!!
- ◆ 2 - Neutralize the charge built-up
 - Reduce the bias frequency and pulse the bias power.
 - During the "Off" period, surface potential decreases.
 - Electrons accelerate toward the surface and neutralize the positive charges at the bottom.
 - Less charge => less trajectory bending
=> smaller notches



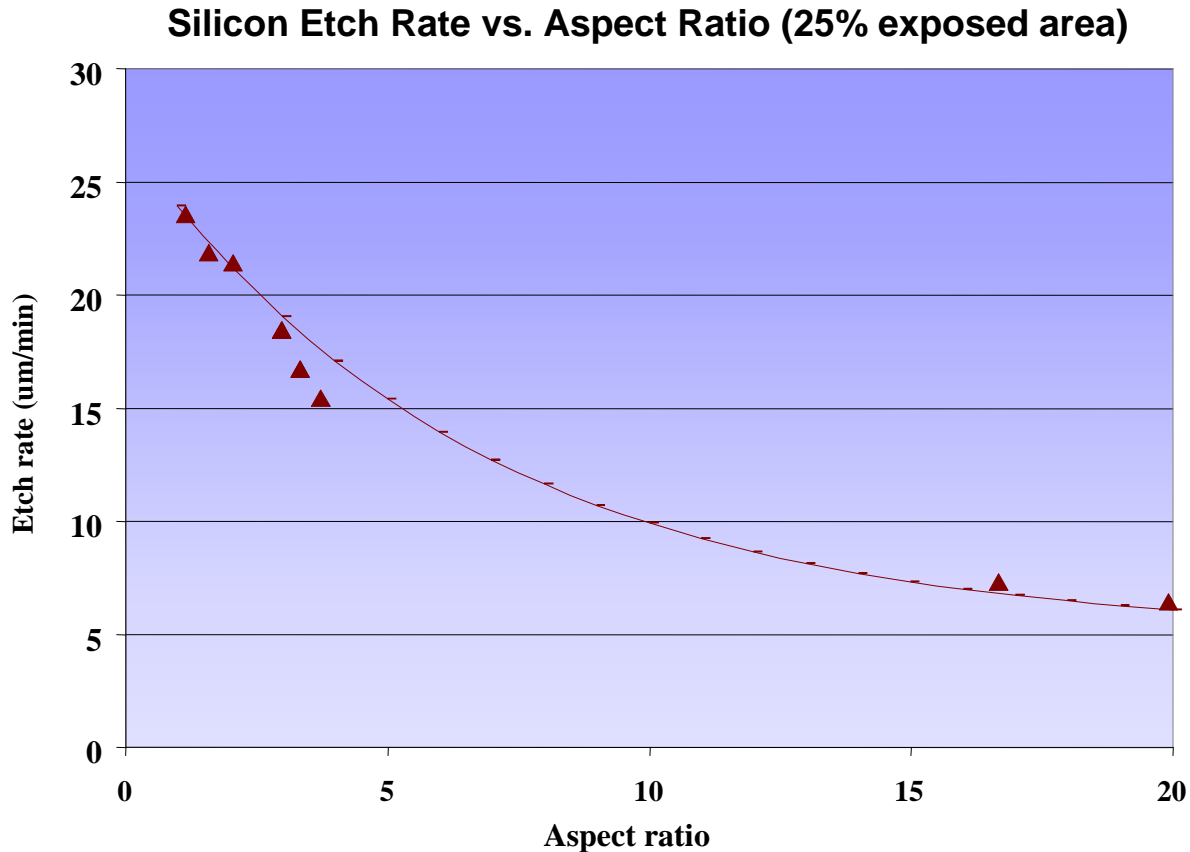
Tegal DRIE process technology can suppress notch formation on SOI substrates

ARDE Control in Si Etching

- ◆ Aspect Ratio Dependent Etching (ARDE): etch rate decreases when A.R increases.
- ◆ Most MEMS devices include structures with a wide range of feature sizes, which can have different etch rates.
- ◆ High over-etching time is required to complete the etching of the narrow features.

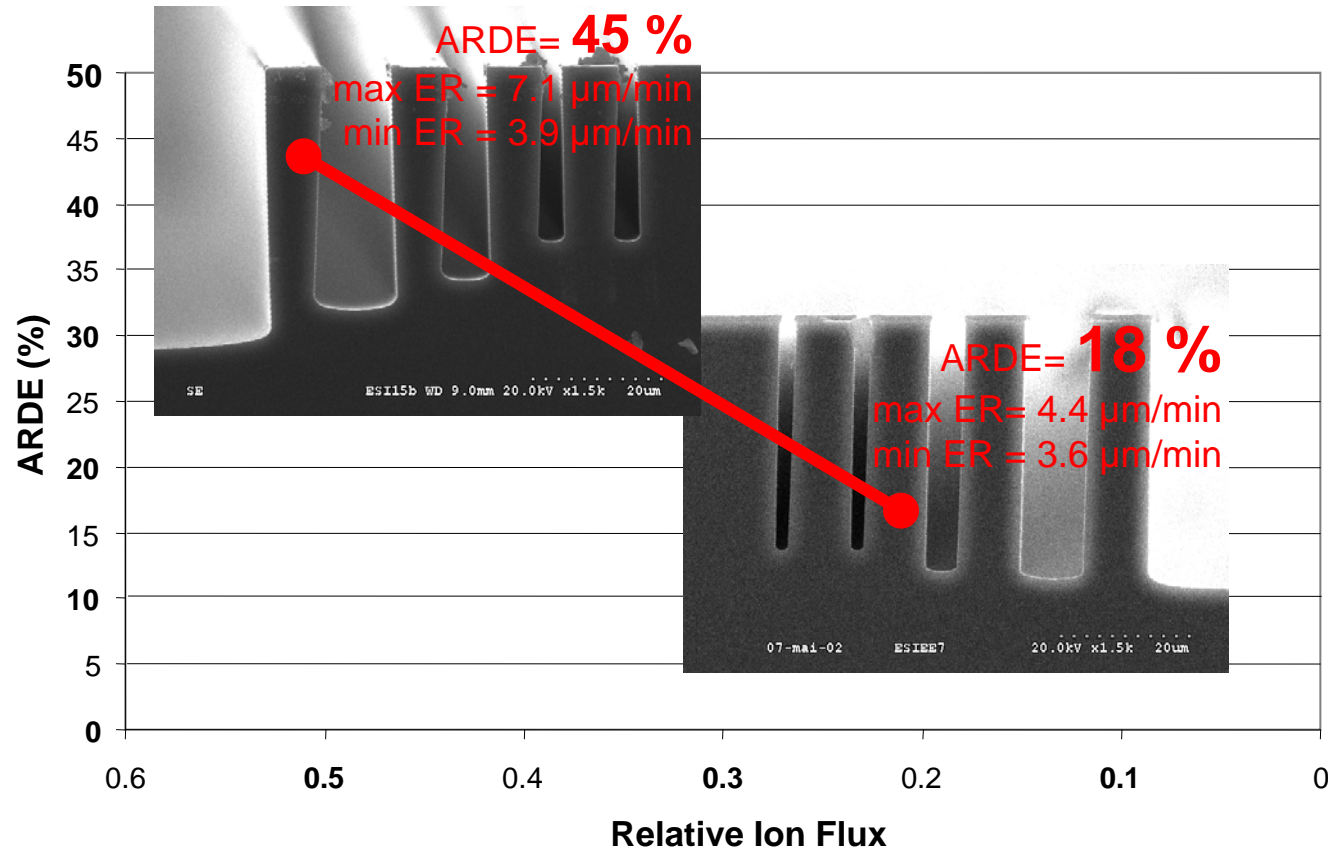


Silicon DRIE - ARDE



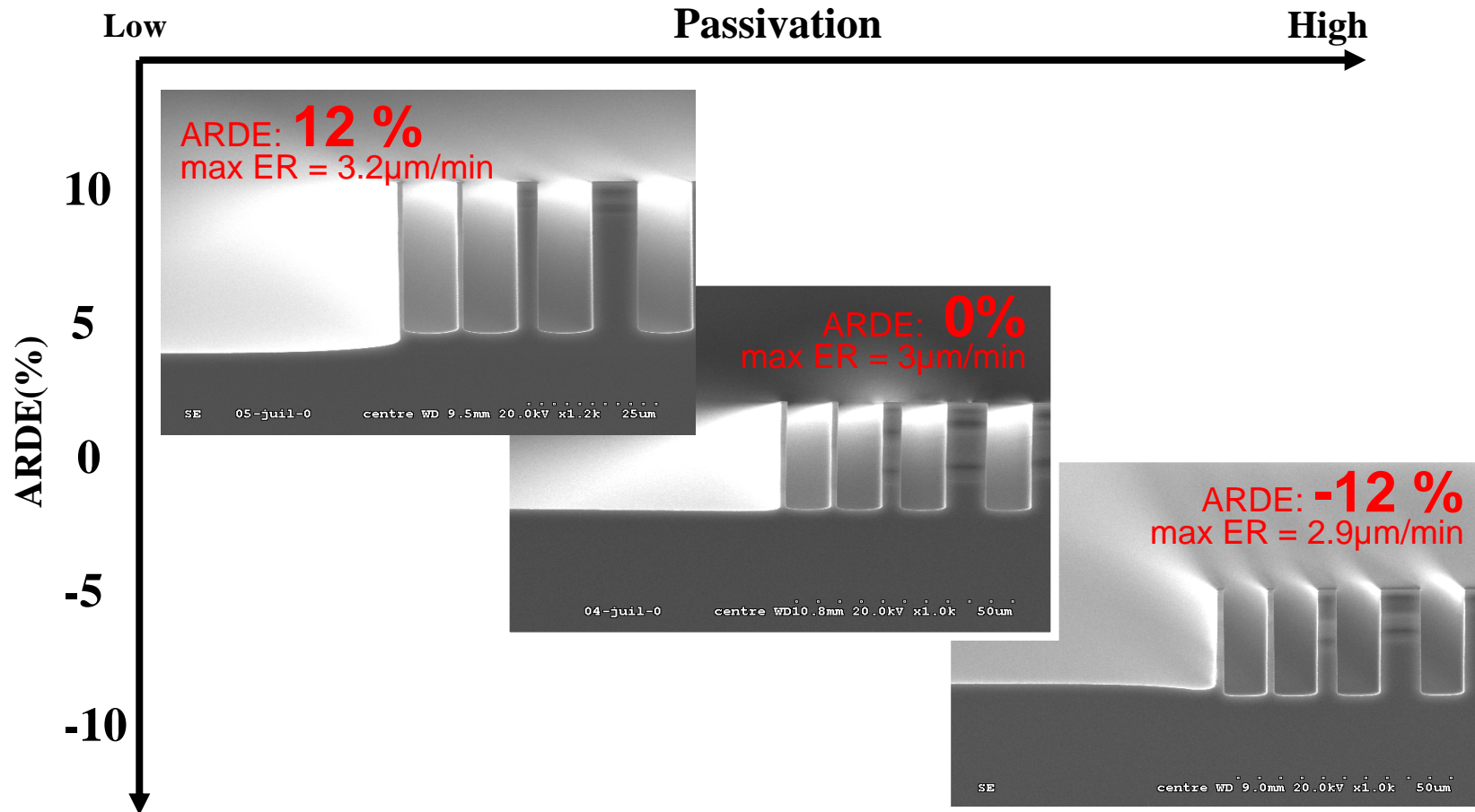
Aspect Ratio Dependent Etch rate: Higher Aspect Ratios result in lower etch rates

ARDE: Role of Ions



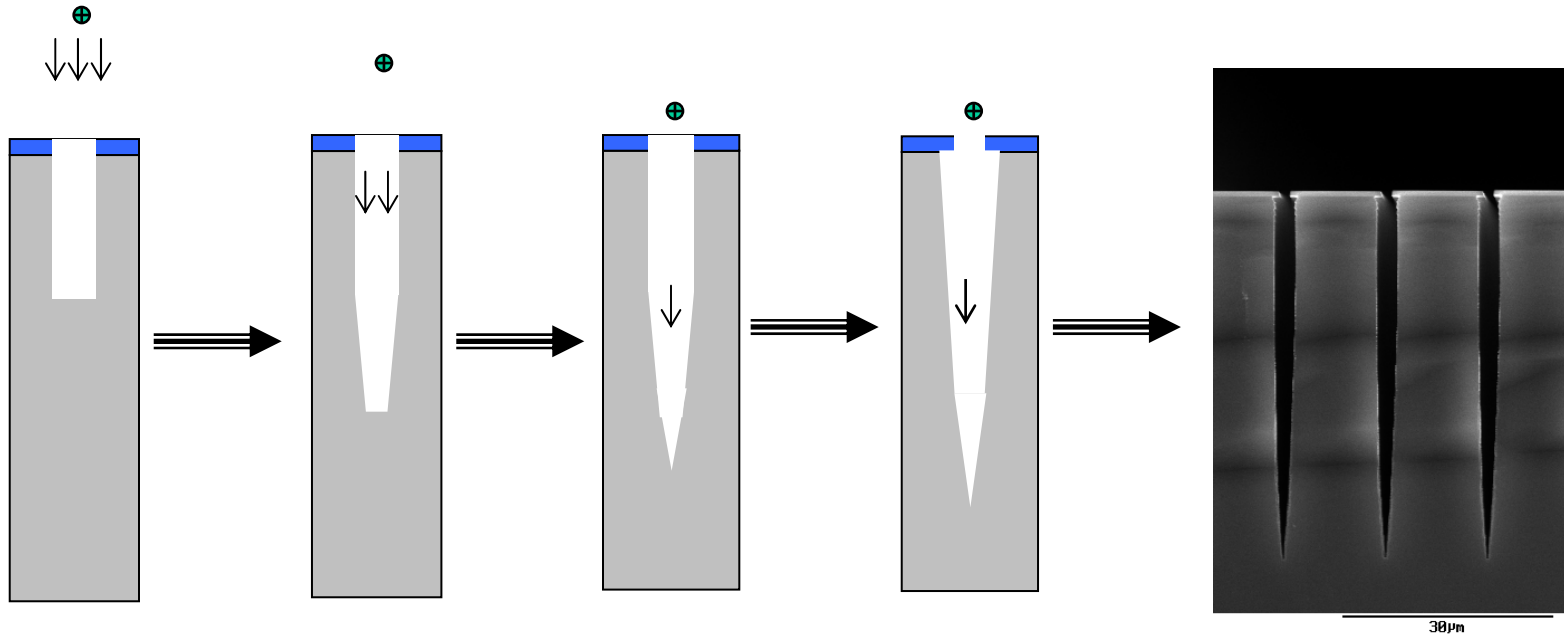
Decreasing the Ion flux reduces the effect of
ARDE

ARDE: Role of passivation



Further ARDE improvement can be made by
modification of the passivation process

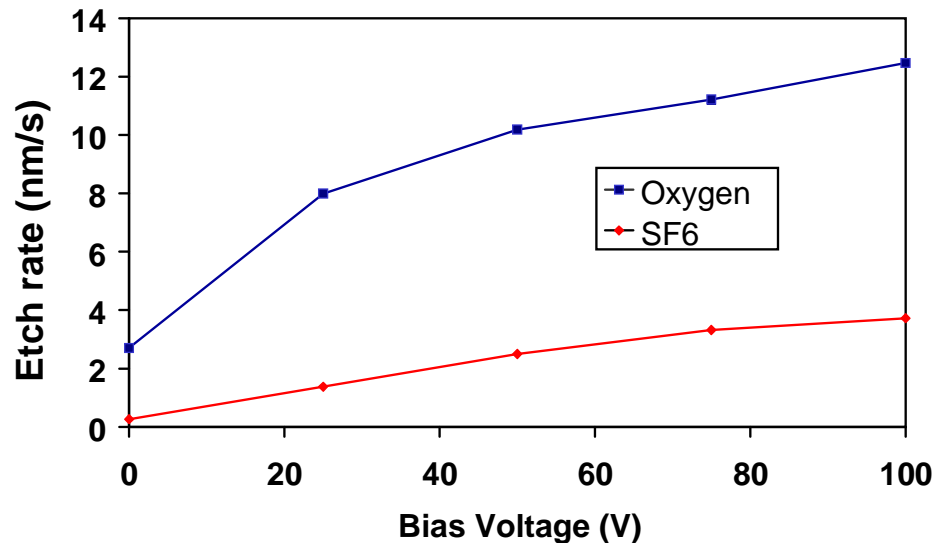
High Aspect Ratio limitation



The standard Bosch process is limited to an aspect ratio of ~20.

The Tegal SHARP Process

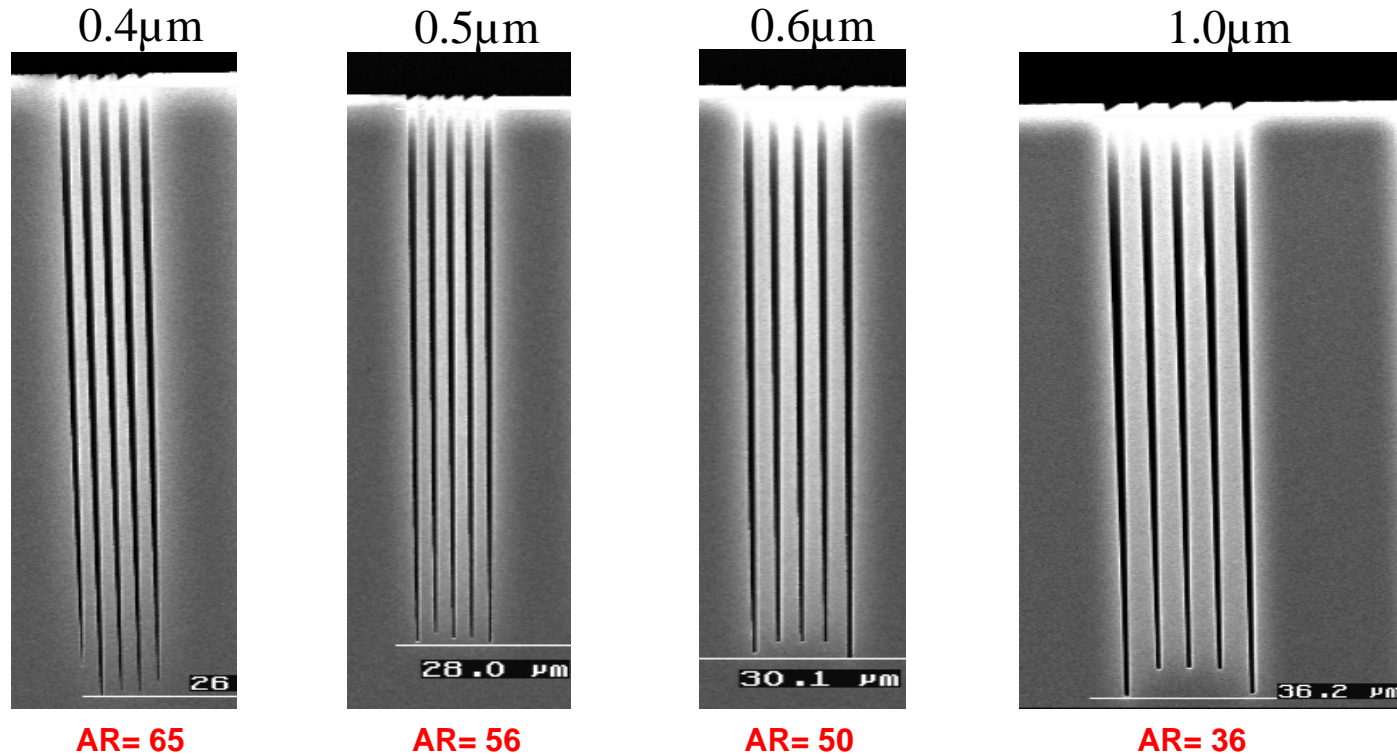
- ◆ Standard solutions for increasing the maximum aspect ratio are inefficient. (pressure, bias, ion flux)



An O₂ Plasma removes polymer 5 time faster than an SF₆ plasma.

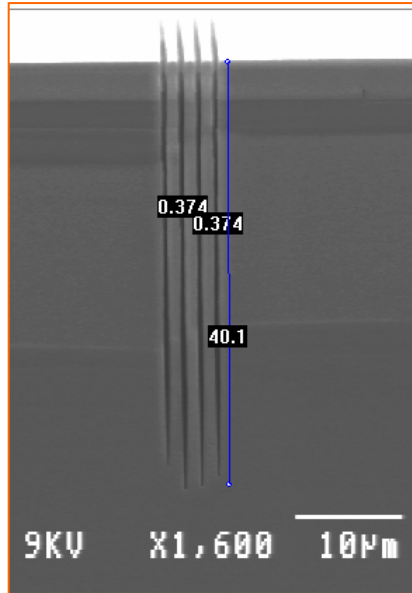
SHARP*: Super High Aspect Ratio Process

*Patent pending



Insertion of an O_2 step into a standard Bosch process sequence optimizes polymer removal. Aspect Ratios of 100:1 can be achieved.

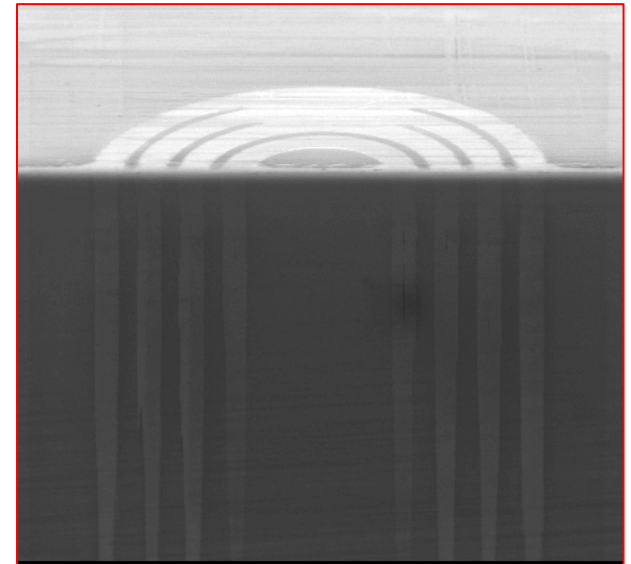
Super High Aspect Ratio Process (SHARP)



Courtesy: ESIEE

AR= 107

SHARP Patented Process
Achieving Aspect Ratio
> 100

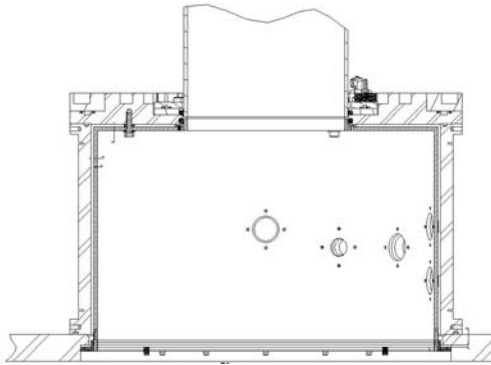


Courtesy: CEA .LETI

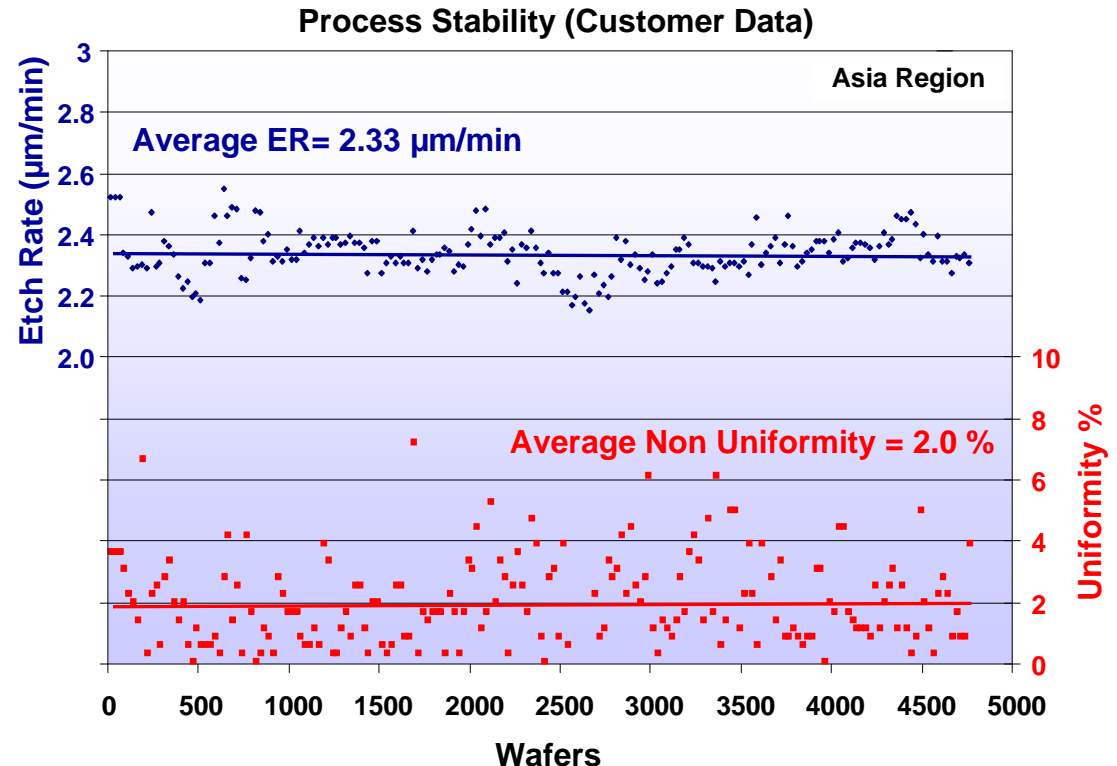
Selective and faster removal of the polymer layer
improves high aspect ratio etching

Process Stability

- ◆ Passivation polymers deposit on all the cooled reactor surfaces.
- ◆ Accumulation of polymers can produce process drift.



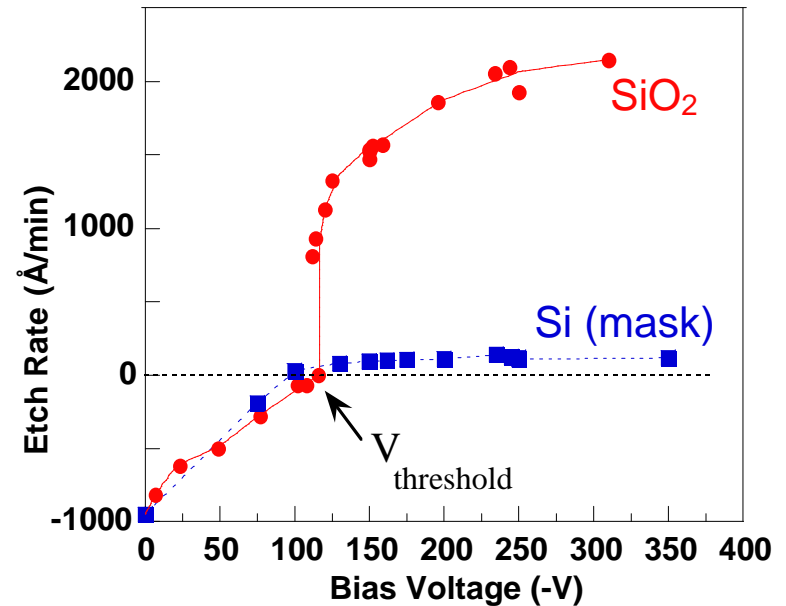
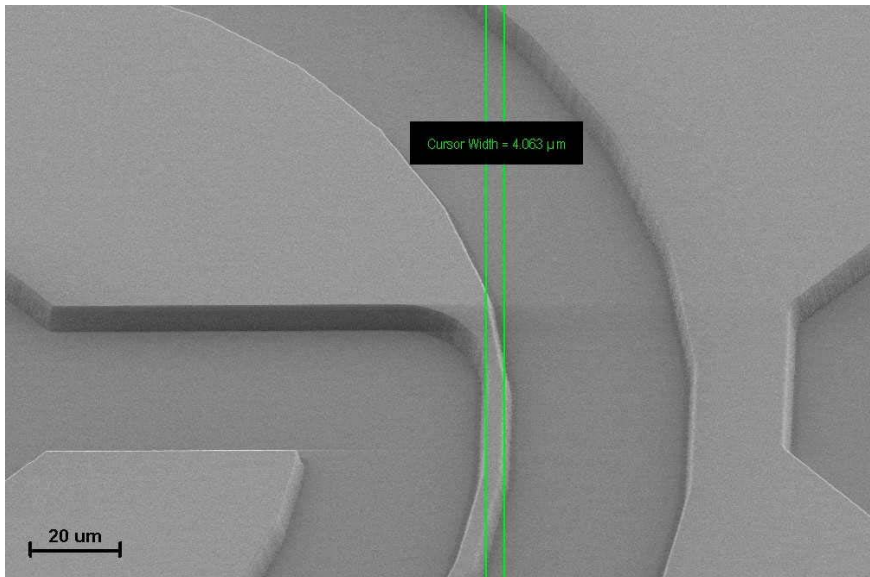
- ◆ Tegal chamber walls are temperature controlled to reduce polymer layer built up.
- ◆ Less frequent “wet” cleans are required.



Reactor design improves process stability and reduces manual cleaning downtime.

Thick Oxide & Glass Etching

- ◆ Deep etching of glass materials
- ◆ Bias Voltage optimized
- ◆ Etch Rate > 0.4 $\mu\text{m}/\text{min}$
- ◆ Selectivity > 18:1



Tegal DRIE can also etch deep oxide features.

- ◆ DRIE of silicon is a key enabling technology for MEMS.
- ◆ Significant DRIE improvements have been discussed:
 - Improved gas utilization and etch rate (Hardware)
 - Angle deviation (Process & Hardware)
 - Improved thermal dissipation (Hardware)
 - Notching control (Process & Hardware)
 - Improved ARDE (Process)
 - SHARP (Process)
 - Improved Process Stability (Hardware)

Tegal Corporation

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Questions?



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Plasma Etch Users Group, 26 February, 2009

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